

# SG40T120DB

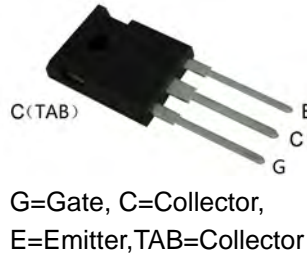
## Discrete IGBTs

$$V_{CES} = 1200V$$

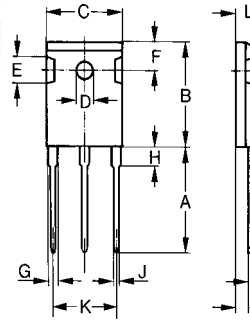
$$I_{C100} = 40A$$

$$V_{CE(sat)} \leq 2.9V$$

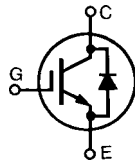
$$t_{fi(typ)} = 60ns$$



Dimensions TO-247AD



Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	19.81	20.32	0.780	0.800
B	20.80	21.46	0.819	0.845
C	15.75	16.26	0.610	0.640
D	3.55	3.65	0.140	0.144
E	4.32	5.49	0.170	0.216
F	5.4	6.2	0.212	0.244
G	1.65	2.13	0.065	0.084
H	-	4.5	-	0.177
J	1.0	1.4	0.040	0.055
K	10.8	11.0	0.426	0.433
L	4.7	5.3	0.185	0.209
M	0.4	0.8	0.016	0.031
N	1.5	2.49	0.087	0.102



SG40T120DB

### IGBT

Symbol	Test Conditions	Maximum Ratings	Unit
$V_{CES}$ $V_{CGR}$	$T_J=25^{\circ}C$ to $150^{\circ}C$ $T_J=25^{\circ}C$ to $150^{\circ}C$ ; $R_{GE}=1 M\Omega$ ;	1200 1200	V
$V_{GES}$ $V_{GEM}$	Continuous Transient	$\pm 20$ $\pm 30$	V
$I_{C25}$ $I_{C100}$ $I_{CM}$	$T_C=25^{\circ}C$ ; limited by leads $T_C=100^{\circ}C$ $T_C=25^{\circ}C$ , 1 ms	60 40 180	A
<b>SSOA</b> <b>(RBSOA)</b>	$V_{GE}=15V$ ; $T_{VJ}=125^{\circ}C$ ; $R_G=5 \Omega$ Clamped inductive load	$I_{CM}=120$ @ 0.8 $V_{CES}$	A
$P_c$	$T_C=25^{\circ}C$	300	W
$T_J$ $T_{JM}$ $T_{stg}$		-55...+150 150 -55...+150	$^{\circ}C$
	Maximum lead temperature for soldering 1.6 mm (0.062 in.) from case for 10s Maximum Tab temperature for soldering SMD devices for 10s	300 260	$^{\circ}C$
$M_d$	Mounting torque (M3)	1.13/10	Nm/lb.in.
<b>Weight</b>	Typical	6	g

( $T_J=25^{\circ}C$ , unless otherwise specified)

Symbol	Test Conditions	Characteristic Values			Unit
		min.	typ.	max.	
$BV_{CES}$	$I_C=1mA$ ; $V_{GE}=0V$	1200			V
$V_{GE(th)}$	$I_C=750\mu A$ ; $V_{CE}=V_{GE}$	5.0	5.8	6.5	V
$I_{CES}$	$V_{CE}=V_{CES}$ ; $T_J=25^{\circ}C$ $V_{GE}=0V$ ; $T_J=125^{\circ}C$			250 4	$\mu A$ mA
$I_{GES}$	$V_{CE}=0V$ ; $V_{GE}=\pm 20V$			$\pm 200$	nA
$V_{CE(sat)}$	$I_C=I_{C90}$ ; $V_{GE}=15V$		2.7	2.9	V



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(T<sub>J</sub>=25°C, unless otherwise specified)

Symbol	Test Conditions	Characteristic Values			Unit
		min.	typ.	max.	
g <sub>ts</sub>	I <sub>C</sub> =I <sub>C90</sub> ; V <sub>CE</sub> =10V Pulse test, t <sub>on</sub> ≤300us, duty cycle≤2%	33	44		S
I <sub>C(ON)</sub>	V <sub>GE</sub> =10V; V <sub>CE</sub> =10V		220		A
C <sub>ies</sub> C <sub>oes</sub> C <sub>res</sub>	V <sub>CE</sub> =25V; V <sub>GE</sub> =0V; f=1MHz		8000 200 120		pF
Q <sub>g</sub> Q <sub>ge</sub> Q <sub>gc</sub>	I <sub>C</sub> =I <sub>C90</sub> ; V <sub>GE</sub> =15V; V <sub>CE</sub> =0.5V <sub>CES</sub>		170 28 57		nC
t <sub>d(on)</sub> t <sub>ri</sub> t <sub>d(off)</sub> t <sub>fi</sub> E <sub>off</sub>	Inductive load, T <sub>J</sub> =25°C I <sub>C</sub> =I <sub>C90</sub> ; V <sub>GE</sub> =15V; V <sub>CE</sub> =0.8V <sub>CES</sub> ; R <sub>G</sub> =R <sub>off</sub> =5Ω Remarks:Switching times may increase for V <sub>CE</sub> (Clamp) > 0.8V <sub>CES</sub> higher T <sub>J</sub> or increased R <sub>G</sub>		80 82 340 60 2	400	ns ns ns ns mJ
t <sub>d(on)</sub> t <sub>ri</sub> E <sub>on</sub> t <sub>d(off)</sub> t <sub>fi</sub> E <sub>off</sub>	Inductive load, T <sub>J</sub> =125°C I <sub>C</sub> =I <sub>C90</sub> ; V <sub>GE</sub> =15V; V <sub>CE</sub> =0.8V <sub>CES</sub> ; R <sub>G</sub> =R <sub>off</sub> =5Ω Remarks:Switching times may increase for V <sub>CE</sub> (Clamp) > 0.8V <sub>CES</sub> higher T <sub>J</sub> or increased R <sub>G</sub>		68 75 2.5 400 160 2.5	2.9	ns ns mJ ns ns mJ
R <sub>thJC</sub>				0.42	K/W
R <sub>thCK</sub>			0.25		K/W

### Reverse Diode (FRED)

(T<sub>J</sub>=25°C, unless otherwise specified)

Symbol	Test Conditions	Characteristic Values			Unit
		min.	typ.	max.	
V <sub>F</sub>	I <sub>F</sub> =40A; T <sub>VJ</sub> =150°C T <sub>VJ</sub> =25°C		2.9 3.3		V
I <sub>RM</sub>	V <sub>R</sub> =100V; I <sub>F</sub> =40A; -di <sub>F</sub> /dt=100A/us L≤0.05uH; T <sub>VJ</sub> =100°C		12		A
t <sub>rr</sub>	I <sub>F</sub> =1A; -di <sub>F</sub> /dt=50A/us; V <sub>R</sub> =30V; T <sub>J</sub> =25°C		40		ns
R <sub>thJC</sub>	Diode		1.1	1.2	K/W



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## Discrete IGBTs

### Features

- Trench Field Stop IGBT technology
- Low switching losses
- Switching frequency up to 30 kHz
- Square RBSOA, no latch up
- High short circuit capability
- Positive temperature coefficient for easy paralleling
- MOS input, voltage controlled
- Ultra fast free wheeling diodes

### Application

- AC and DC motor control
- AC servo and robot drives
- power supplies
- welding inverters

### Advantages

- space and weight savings
- reduced protection circuits

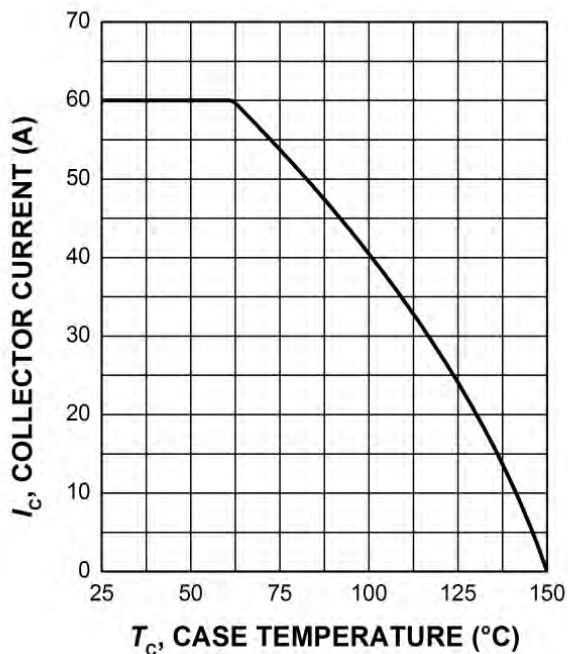


Figure 1. Maximum collector current as a function of case temperature ( $V_{GE} \geq 15V$ ,  $T_j \leq 150^\circ C$ )

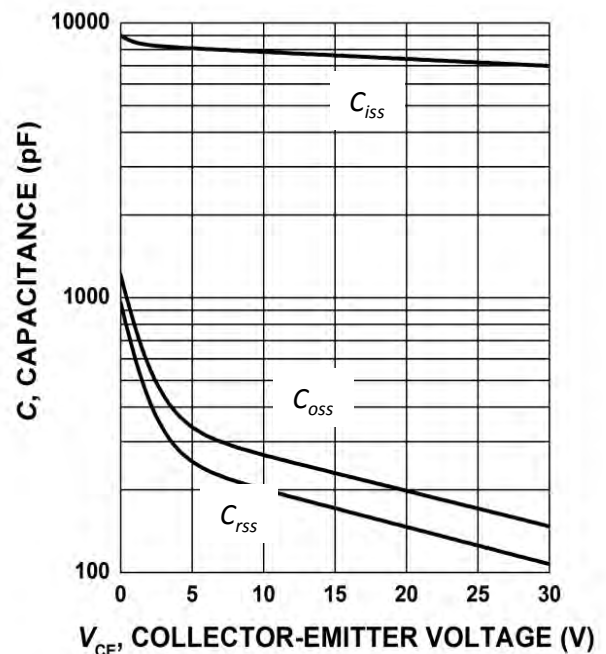


Figure 2. Typical capacitance as a function of collector-emitter voltage ( $V_{GE}=0V$ ,  $f = 1$  MHz)



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## Discrete IGBTs

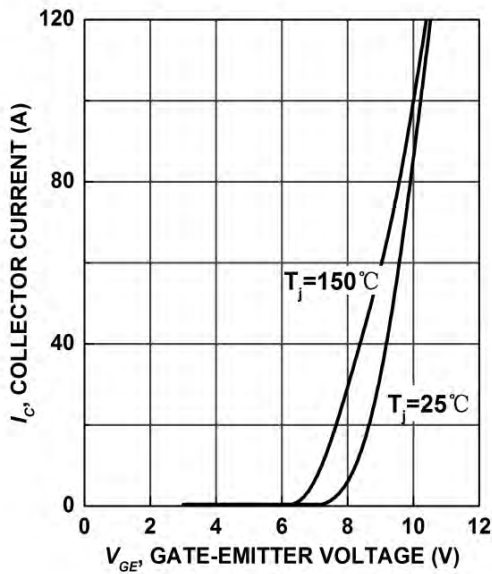


Figure 3. Typical transfer characteristic ( $V_{CE}=15\text{V}$ )

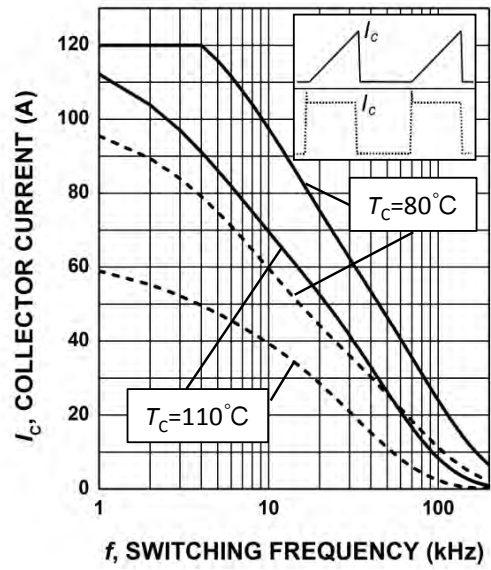


Figure 4. Collector current as a function of switching frequency ( $T_j \leq 150^\circ\text{C}$ ,  $D = 0.5$ ,  $V_{CE} = 600\text{V}$ ,  $V_{GE} = 0/+15\text{V}$ ,  $R_G = 12\Omega$ )

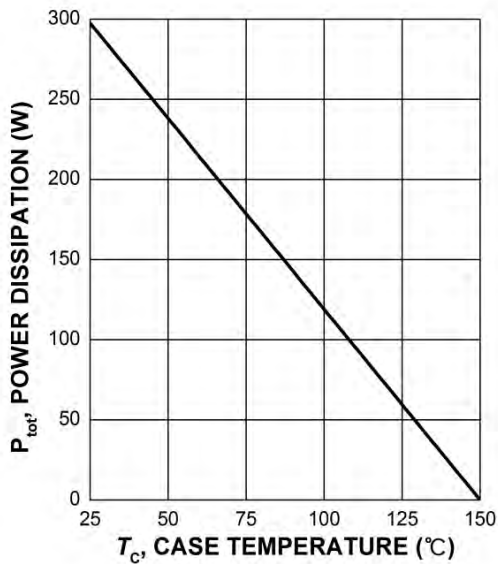


Figure 5. Maximum power dissipation as a function of case temperature ( $T_j \leq 150^\circ\text{C}$ )

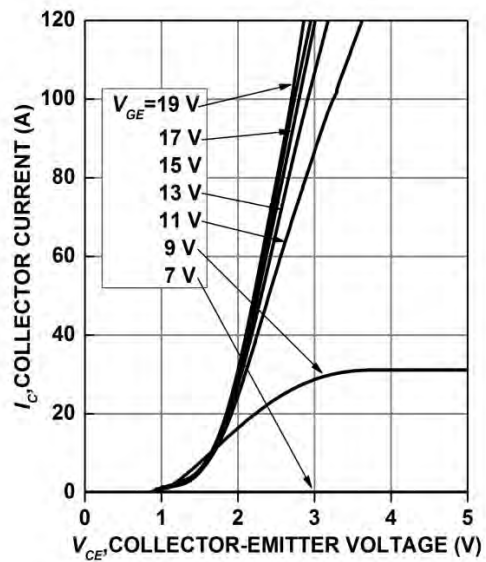


Figure 6. Typical output characteristic ( $T_j = 25^\circ\text{C}$ )

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## Discrete IGBTs

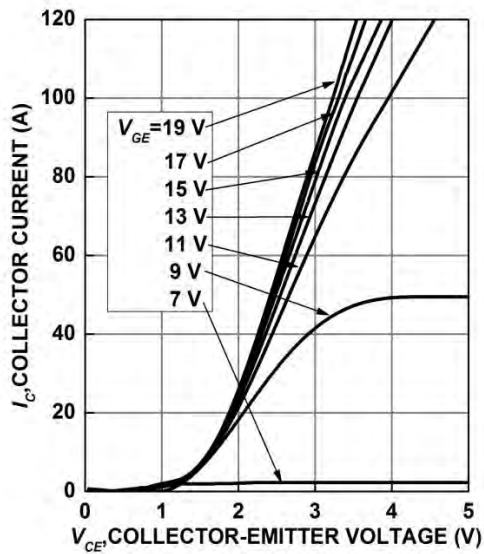


Figure 7. Typical output characteristic ( $T_j = 150^\circ\text{C}$ )

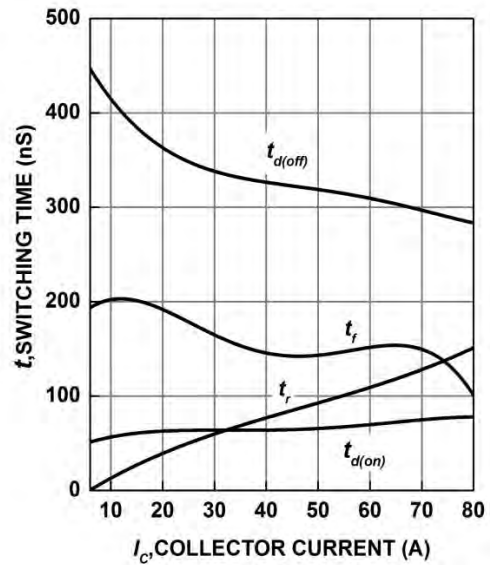


Figure 8. Typical switching times as a function of collector current (inductive load,  $T_j=150^\circ\text{C}$ ,  $V_{CE}=600\text{V}$ ,  $V_{GE}=0/15\text{V}$ ,  $R_G=12\Omega$ , Dynamic test circuit in Figure D)

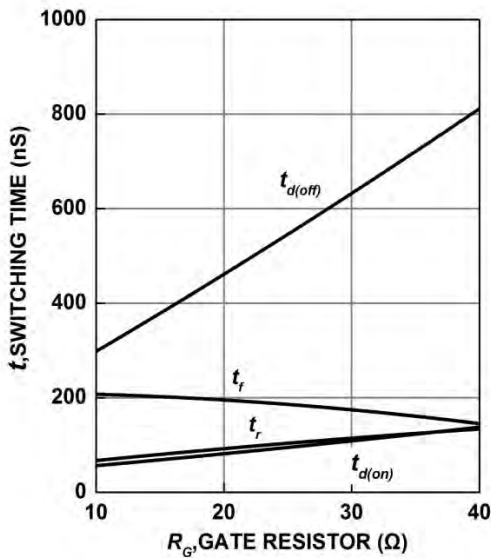


Figure 9. Typical switching times as a function of gate resistor (inductive load,  $T_j=150^\circ\text{C}$ ,  $V_{CE}=600\text{V}$ ,  $V_{GE}=0/15\text{V}$ ,  $I_C=40\text{A}$ , Dynamic test circuit in Figure D)

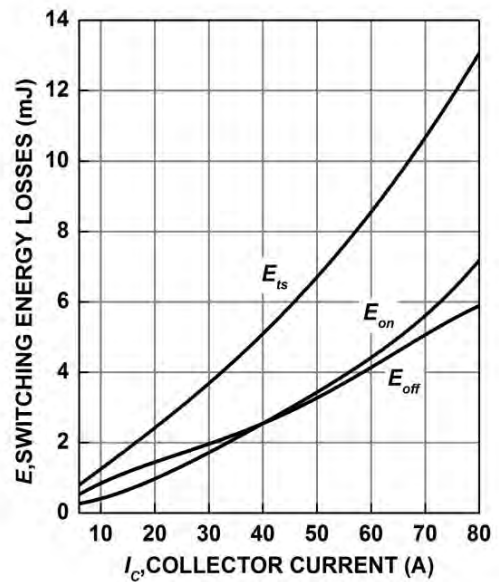


Figure 10. Typical switching energy losses as a function of collector current (inductive load,  $T_j=150^\circ\text{C}$ ,  $V_{CE}=600\text{V}$ ,  $V_{GE}=0/15\text{V}$ ,  $R_G=12\Omega$ , Dynamic test circuit in Figure D)



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## Discrete IGBTs

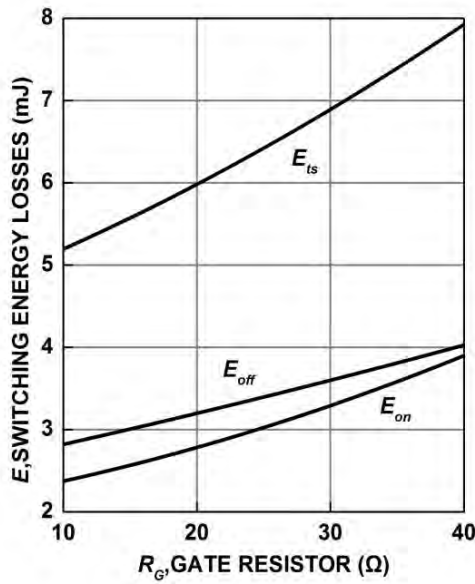


Figure 11. Typical switching energy losses as a function of gate resistor (inductive load,  $T_j=150^{\circ}\text{C}$ ,  $V_{\text{CE}}=600\text{V}$ ,  $V_{\text{GE}}=0/15\text{V}$ ,  $I_{\text{C}}=40\text{A}$ , Dynamic test circuit in Figure D)

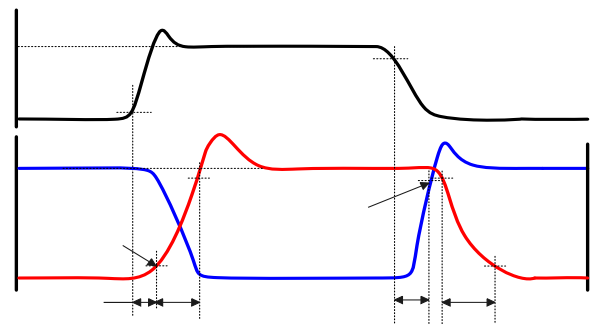


Figure A. Definition of switching times

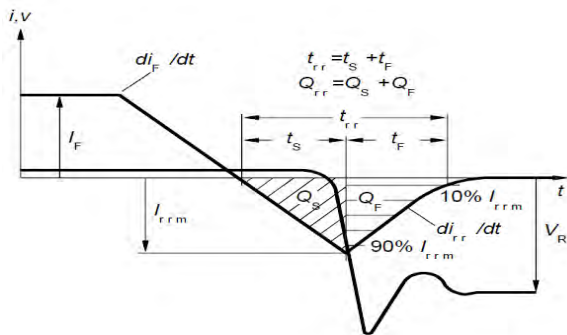


Figure C. Definition of diodes switching characteristics

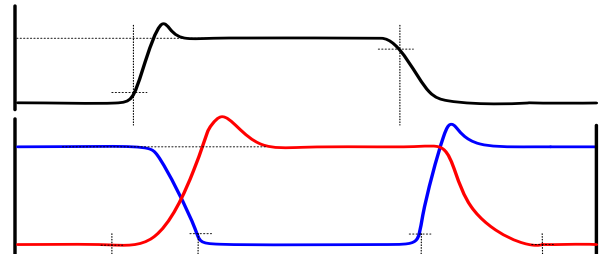


Figure B. Definition of switching losses

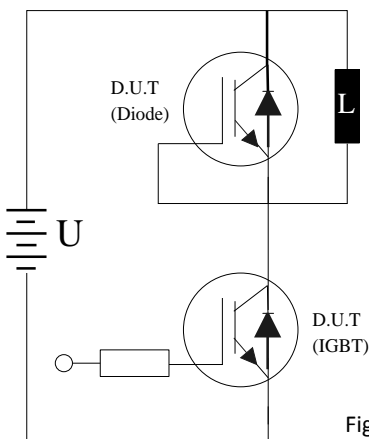


Figure D. Dynamic test circuit